



# DE-16 Camera System

the most versatile direct detector available

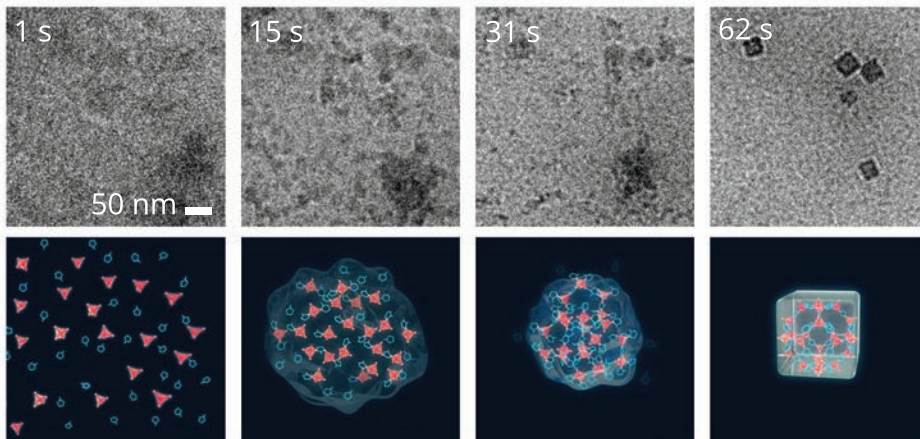
delivering | bigger | better | faster | cameras for electron microscopy

## TEM Direct Detection with Stunning Sensitivity

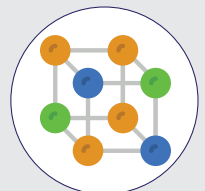
- The most advanced direct detection sensors, delivering high speed, extraordinary resolution, and ultra-low noise.
- Superior DQE delivers higher resolution and better contrast for high-speed single frames.
- 4k × 4k (16.8 million) pixels.
- High-speed continuous streaming for *in situ* TEM, 4D STEM, and microED.
- Global shutter eliminates artifacts in high-speed applications.
- Versatility for a wide range of TEM experiments.
- Electron counting to maximize SNR for low-dose applications.
- High-dynamic range (HDR) counting for 4D STEM & EELS.
- Optional ER sensor optimized for 30 - 300 kV.



Metal-organic framework (MOF) formation via liquid phase *in situ* TEM using a DE-16 camera in counting mode with an ultra-low beam dose of 0.05 e<sup>-</sup>/Å<sup>2</sup>/s. Figure based on Liu, et. al 2021 (<https://doi.org/10.1073/pnas.2008880118>).



Applications



MATERIALS



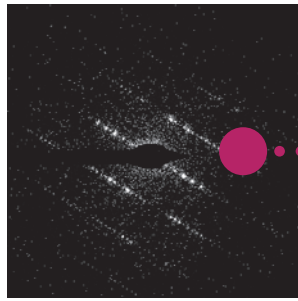
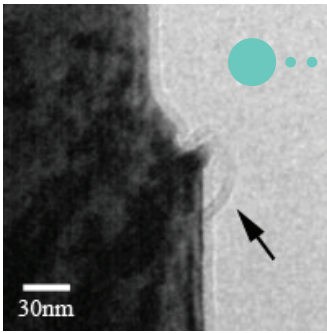
BIOLOGY

Direct Electron<sup>®</sup>  
INNOVATION PROPELLING DISCOVERY

# Optimized for Demanding TEM Applications

## *in situ* TEM & Environmental TEM (ETEM)

high-speed movies with exceptional contrast

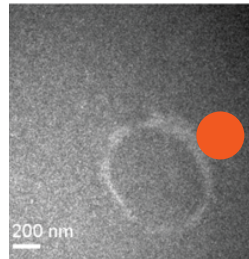
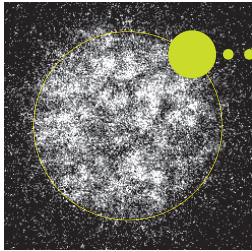


## Diffraction/MicroED

high dynamic range & high speed streaming

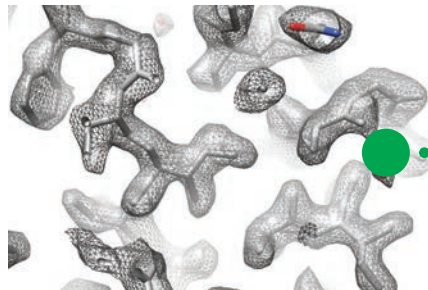
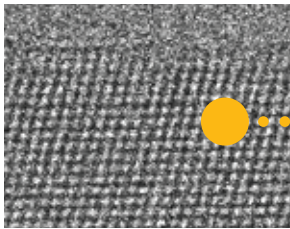
## 4D STEM/Ptychography

fast, large-area pixelated STEM detector



## DTEM/UTEM & EFTEM

phenomenal sensitivity over long exposure times



## Single-Particle Cryo-EM

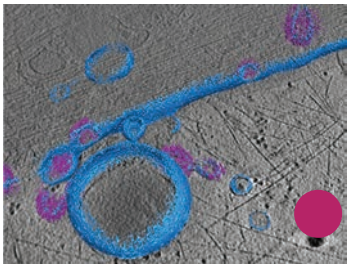
high-resolution 3D reconstructions

## Low-Dose Imaging

exceptional SNR with electron counting

## High-Resolution Tomography

conventional or continuous-rotation acquisition



# The Most Advanced Direct Detection Sensor Technology

**hardware binning and ROI**  
to increase frame rate up to  
4,237 fps (236  $\mu$ s / frame)

**user-adjustable frame rate**  
in hardware to optimize SNR  
by reducing readout noise

**hardware sync I/O**  
for high-speed synchronization of  
other hardware (e.g., scan generator)  
with the camera frame rate

**global shutter mode**  
to eliminate high-speed artifacts  
that affect other CMOS cameras

**on-chip CDS**  
for the lowest noise and  
best SNR at high-speed

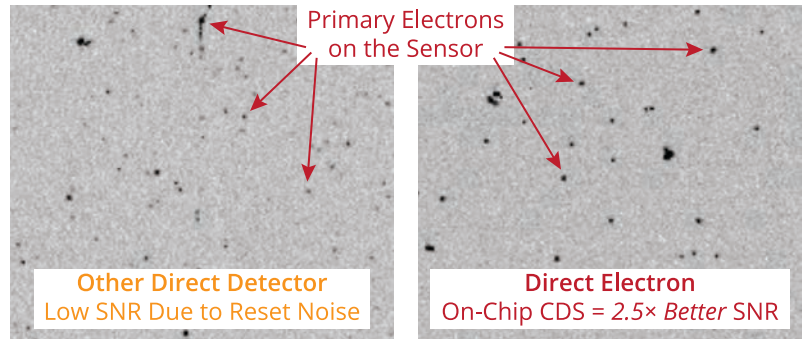
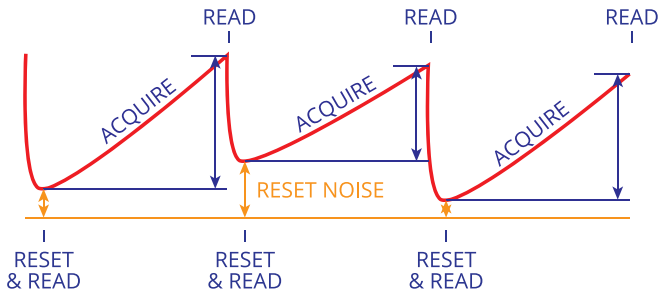
**ER sensor option**  
for direct detection at all  
TEM accelerating voltages

**access to all camera frames**  
at full-speed and full-resolution  
without significant delays

*Can your  
direct detector  
do this?*

**compressive sensing**  
readout modes to further  
boost readout speed

# Advanced Sensor Technology to Deliver the Best Sensitivity



**on-chip correlated double sampling (CDS)** dramatically improves sensitivity by subtracting reset noise that plagues other CMOS sensors

Direct Electron's DDD® sensors have ultra-low noise, which is clearly demonstrated by visualizing individual 300 keV electrons. TEM primary electrons clearly stand-out from the background on the Direct Electron sensor, while they are often lost in the background of other sensors. *Figure courtesy of Greg McMullan, (MRC-LMB, Cambridge, UK).*

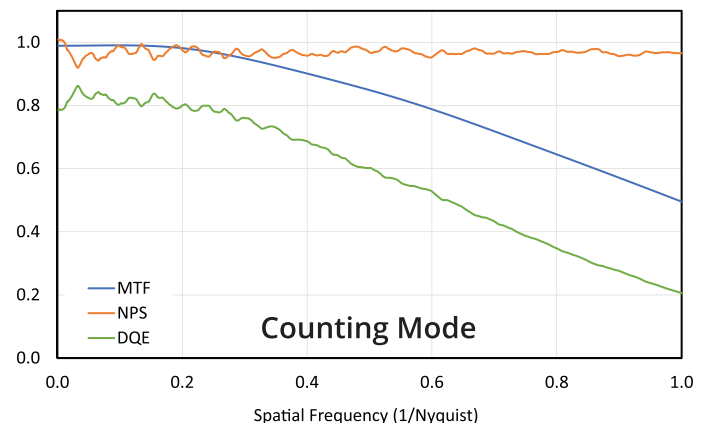
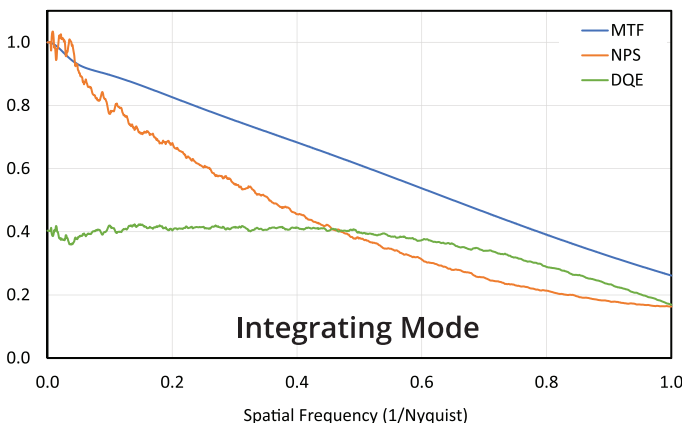
# Elegantly-Designed to Maximize Scientific Productivity

The diagram shows a cross-section of a camera assembly with several components labeled with callouts:

- photoblind option** to prevent detection of photons (especially for DTEM/UTEM applications)
- integrated Faraday plate** for exposure measurement with each acquisition (*US patent #7,952,073*)
- sensor protection shutter** to protect the direct detection sensor from undesired exposure (*US patent #7,952,073*)
- high-performance 10th generation DDD® sensor** custom-designed and manufactured by Direct Electron
- precision-engineered parts** that are widely compatible with TEMs from many manufacturers
- field-replaceable sensor** to maximize instrument uptime over the lifetime of the camera
- fully retractable** to enable use of other cameras and/or an energy filter mounted under the DE camera
- no sliding O-rings** to prevent vacuum "hiccups" during insertion/retraction



<b>TEM electron energy</b>	standard sensor optimized for 200 - 300 keV   ER sensor optimized for 30 - 300 keV
<b>pixel array specification</b>	4096 × 4096 (16.8 million pixels)   6.5 μm pixel pitch
<b>single electron SNR</b>	~50:1 (300 kV)
<b>sensor design</b>	custom-designed DDD® sensor on-chip correlated double sampling (CDS)   backthinned   radiation hardened
<b>acquisition frame rate</b>	92 fps max, unbinned full-frame   281 fps max, binned-2× full-frame, low-noise subarray readout up to 4,237 fps (2048 × 128)   user-selectable hardware frame rate
<b>readout modes</b>	rolling with on-chip CDS   global with optional off-chip CDS
<b>acquisition modes</b>	integrating mode   electron counting mode HDR counting mode (US patent #11,252,339)
<b>exposure rate</b>	large dynamic range with consistent performance (e.g., >10,000 e <sup>-</sup> /pixel/s)
<b>TEM compatibility</b>	all major TEM manufacturers & models   DE-FreeScan requires STEM capability
<b>mounting position</b>	fully retractable   compatible with a wide-range of configurations typically in TEM bottom port, pre- or post-energy filter, or in JEOL film drawer
<b>sensor protection</b>	sensor protection shutter   TEM blanking/shuttering   failsafe software
<b>computer system</b>	high-performance computer   Windows 10   Nvidia GPU(s)   up to 55 TB storage
<b>image format</b>	non-proprietary   HDF5, MRC, TIFF, or TIFF LZW compatible with ImageJ, LiberTEM, Hyperspy, Py4DSTEM, etc.
<b>automation software integrations</b>	SerialEM   open API for custom integrations (with Python, C, C++, C#, etc.) CEFID post-column energy filter (CEOS)   precession diffraction (Nanomegas)
<b>scan control</b>	DE-FreeScan scan controller (also includes 4 analog detector inputs) hardware synchronization signal (BNC)   selectable as either input or output



DQE curves are shown for 300 kV electrons | Specifications and performance are subject to change.

Example images of various camera applications were collected by researchers using one of Direct Electron's cameras (not necessarily the DE-16).

